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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Not For New Designs
Core Processor	ARM® Cortex®-M3
Core Size	32-Bit Single-Core
Speed	32MHz
Connectivity	I²C, IrDA, LINbus, SPI, UART/USART, USB
Peripherals	Brown-out Detect/Reset, Cap Sense, DMA, I²S, POR, PWM, WDT
Number of I/O	51
Program Memory Size	128KB (128K x 8)
Program Memory Type	FLASH
EEPROM Size	4K x 8
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 3.6V
Data Converters	A/D 20x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	64-LQFP
Supplier Device Package	64-LQFP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32l151rbt6

1 Introduction

This datasheet provides the ordering information and mechanical device characteristics of the STM32L151x6/8/B and STM32L152x6/8/B ultra-low-power ARM® Cortex®-M3 based microcontrollers product line.

The ultra-low-power STM32L151x6/8/B and STM32L152x6/8/B family includes devices in 3 different package types: from 48 to 100 pins. Depending on the device chosen, different sets of peripherals are included, the description below gives an overview of the complete range of peripherals proposed in this family.

These features make the ultra-low-power STM32L151x6/8/B and STM32L152x6/8/B microcontroller family suitable for a wide range of applications:

- Medical and handheld equipment
- Application control and user interface
- PC peripherals, gaming, GPS and sport equipment
- Alarm systems, Wired and wireless sensors, Video intercom
- Utility metering

This STM32L151x6/8/B and STM32L152x6/8/B datasheet should be read in conjunction with the STM32L1xxxx reference manual (RM0038).

The document "Getting started with STM32L1xxxx hardware development" AN3216 gives a hardware implementation overview. Both documents are available from the STMicroelectronics website *www.st.com*.

For information on the ARM® Cortex®-M3 core please refer to the Cortex®-M3 Technical Reference Manual, available from the www.arm.com website.

Figure 1 shows the general block diagram of the device family.

Caution: This datasheet does not apply to STM32L15xx6/8/B-A covered by a separate datasheet.

2.1 Device overview

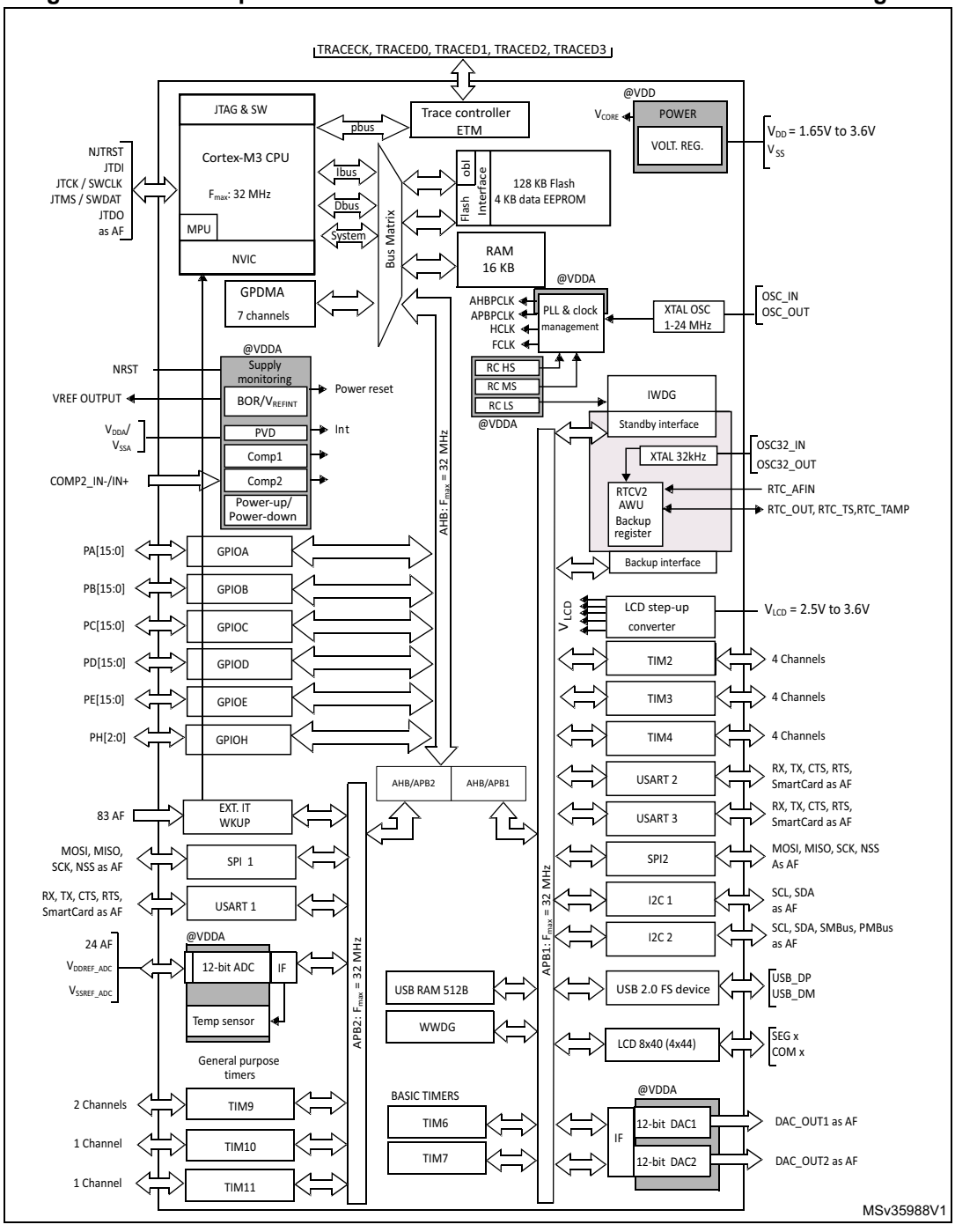
Table 2. Ultra-low-power STM32L151x6/8/B and STM32L152x6/8/B device features and peripheral counts

Peripheral		STM32L15xCx			STM32L15xRx			STM32L15xVx	
Flash (Kbytes)		32	64	128	32	64	128	64	128
Data EEPROM (Kbytes)		4							
RAM (Kbytes)		10	10	16	10	10	16	10	16
Timers	General-purpose	6							
	Basic	2							
Communication interfaces	SPI	2							
	I^2C	2							
	USART	3							
	USB	1							
GPIOs		37			51			83	
12-bit synchronized ADC Number of channels		1 14 channels			1 20 channels			1 24 channels	
12-bit DAC Number of channels		2 2							
LCD (STM32L152xx Only) COM x SEG		4x18			4x32 8x28			4x44 8x40	
Comparator		2							
Capacitive sensing channels		13			20				
Max. CPU frequency		32 MHz							
Operating voltage		1.8 V to 3.6 V (down to 1.65 V at power-down) with BOR option 1.65 V to 3.6 V without BOR option							
Operating temperatures		Ambient temperatures: –40 to +85 °C Junction temperature: –40 to + 105 °C							
Packages		LQFP48, UFQFPN48			LQFP64, BGA64			LQFP100, BGA100	

3 Functional overview

Figure 1 shows the block diagram.

Figure 1. Ultra-low-power STM32L151x6/8/B and STM32L152x6/8/B block diagram



1. AF = alternate function on I/O port pin.

3.1 Low power modes

The ultra-low-power STM32L151x6/8/B and STM32L152x6/8/B devices support dynamic voltage scaling to optimize its power consumption in run mode. The voltage from the internal low-drop regulator that supplies the logic can be adjusted according to the system's maximum operating frequency and the external voltage supply:

- In Range 1 (V_{DD} range limited to 1.71-3.6 V), the CPU runs at up to 32 MHz (refer to *Table 17* for consumption).
- In Range 2 (full V_{DD} range), the CPU runs at up to 16 MHz (refer to *Table 17* for consumption)
- In Range 3 (full V_{DD} range), the CPU runs at up to 4 MHz (generated only with the multispeed internal RC oscillator clock source). Refer to *Table 17* for consumption.

Seven low power modes are provided to achieve the best compromise between low power consumption, short startup time and available wakeup sources:

- **Sleep** mode

  In Sleep mode, only the CPU is stopped. All peripherals continue to operate and can wake up the CPU when an interrupt/event occurs.

  Sleep mode power consumption: refer to *Table 19*.

- **Low power run** mode

  This mode is achieved with the multispeed internal (MSI) RC oscillator set to the minimum clock (65 kHz), execution from SRAM or Flash memory, and internal regulator in low power mode to minimize the regulator's operating current. In the Low power run mode, the clock frequency and the number of enabled peripherals are both limited.

  Low power run mode consumption: refer to *Table 20: Current consumption in Low power run mode*.

- **Low power sleep** mode

  This mode is achieved by entering the Sleep mode with the internal voltage regulator in Low power mode to minimize the regulator's operating current. In the Low power sleep mode, both the clock frequency and the number of enabled peripherals are limited; a typical example would be to have a timer running at 32 kHz.
  When wakeup is triggered by an event or an interrupt, the system reverts to the run mode with the regulator on.

  Low power sleep mode consumption: refer to *Table 21: Current consumption in Low power sleep mode*.

- **Stop** mode with RTC

  Stop mode achieves the lowest power consumption while retaining the RAM and register contents and real time clock. All clocks in the V_{CORE} domain are stopped, the PLL, MSI RC, HSI RC and HSE crystal oscillators are disabled. The LSE or LSI is still running. The voltage regulator is in the low power mode.

  The device can be woken up from Stop mode by any of the EXTI line, in 8 µs. The EXTI line source can be one of the 16 external lines. It can be the PVD output, the Comparator 1 event or Comparator 2 event (if internal reference voltage is on), it can be the RTC alarm(s), the USB wakeup, the RTC tamper events, the RTC timestamp event or the RTC wakeup.

- **Stop** mode without RTC

  Stop mode achieves the lowest power consumption while retaining the RAM and register contents. All clocks are stopped, the PLL, MSI RC, HSI and LSI RC, LSE and

Table 5. Working mode-dependent functionalities (from Run/active down to standby) (continued)

Ips	Run/Active	Sleep	Low-power Run	Low-power Sleep	Stop		Standby	
						Wakeup capability		Wakeup capability
DAC	Y	Y	Y	Y	Y	-	-	-
Temperature sensor	Y	Y	Y	Y	Y	-	-	-
Comparators	Y	Y	Y	Y	Y	Y	-	-
16-bit and 32-bit Timers	Y	Y	Y	Y	-	-	-	-
IWDG	Y	Y	Y	Y	Y	Y	Y	Y
WWDG	Y	Y	Y	Y	-	-	-	-
Touch sensing	Y	-	-	-	-	-	-	-
Systick Timer	Y	Y	Y	Y	-	-	-	-
GPIOs	Y	Y	Y	Y	Y	Y	-	3 Pins
Wakeup time to Run mode	0 µs	0.36 µs	3 µs	32 µs	< 8 µs		50 µs	
Consumption V_{DD}=1.8V to 3.6V (Typ)	Down to 214 µA/MHz (from Flash)	Down to 50 µA/MHz (from Flash)	Down to 9 µA	Down to 4.4 µA	0.5 µA (No RTC) V_{DD}=1.8V		0.3 µA (No RTC) V_{DD}=1.8V	
					1.4 µA (with RTC) V_{DD}=1.8V		1 µA (with RTC) V_{DD}=1.8V	
					0.5 µA (No RTC) V_{DD}=3.0V		0.3 µA (No RTC) V_{DD}=3.0V	
					1.6 µA (with RTC) V_{DD}=3.0V		1.3 µA (with RTC) V_{DD}=3.0V	

1. The startup on communication line wakes the CPU which was made possible by an EXTI, this induces a delay before entering run mode.

3.2 ARM® Cortex®-M3 core with MPU

The ARM® Cortex®-M3 processor is the industry leading processor for embedded systems. It has been developed to provide a low-cost platform that meets the needs of MCU implementation, with a reduced pin count and low-power consumption, while delivering outstanding computational performance and an advanced system response to interrupts.

The ARM® Cortex®-M3 32-bit RISC processor features exceptional code-efficiency, delivering the high-performance expected from an ARM core in the memory size usually associated with 8- and 16-bit devices.

The memory protection unit (MPU) improves system reliability by defining the memory attributes (such as read/write access permissions) for different memory regions. It provides up to eight different regions and an optional predefined background region.

Owing to its embedded ARM core, the STM32L151x6/8/B and STM32L152x6/8/B devices are compatible with all ARM tools and software.

implementation based on a surface charge transfer acquisition principle. It consists of charging the sensor capacitance and then transferring a part of the accumulated charges into a sampling capacitor until the voltage across this capacitor has reached a specific threshold. The capacitive sensing acquisition only requires few external components to operate.

Reliable touch sensing functionality can be quickly and easily implemented using the free STM32L1xx STMTouch touch sensing firmware library.

3.15 Timers and watchdogs

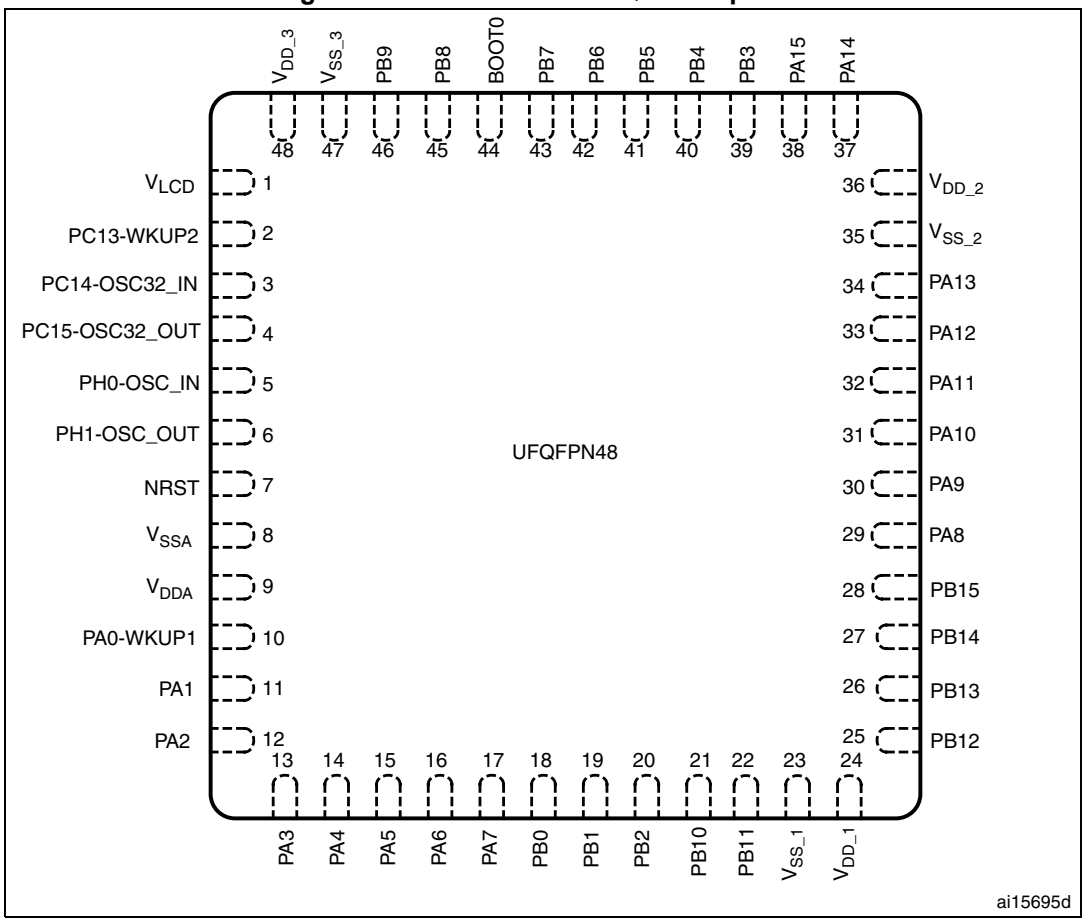
The ultra-low-power STM32L151x6/8/B and STM32L152x6/8/B devices include six general-purpose timers, two basic timers and two watchdog timers.

Table 6 compares the features of the general-purpose and basic timers.

Table 6. Timer feature comparison

Timer	Counter resolution	Counter type	Prescaler factor	DMA request generation	Capture/compare channels	Complementary outputs
TIM2, TIM3, TIM4	16-bit	Up, down, up/down	Any integer between 1 and 65536	Yes	4	No
TIM9	16-bit	Up	Any integer between 1 and 65536	No	2	No
TIM10, TIM11	16-bit	Up	Any integer between 1 and 65536	No	1	No
TIM6, TIM7	16-bit	Up	Any integer between 1 and 65536	Yes	0	No

Figure 8. STM32L15xCx UFQFPN48 pinout



1. This figure shows the package top view.

Table 9. Alternate function input/output

Port name	Digital alternate function number														
	AFIO0	AFIO1	AFIO2	AFIO3	AFIO4	AFIO5	AFOI6	AFIO7	AFIO8	AFIO9	AFIO11	AFIO12	AFIO13	AFIO14	AFIO15
	Alternate function														
	SYSTEM	TIM2	TIM3/4	TIM9/10/11	I2C1/2	SPI1/2	N/A	USART1/2/3	N/A	N/A	LCD	N/A	N/A	RI	SYSTEM
BOOT0	BOOT0	-	-	-	-	-	-	-	-	-	-	-	-	-	-
NRST	NRST	-	-	-	-	-	-	-	-	-	-	-	-	-	-
PA0-WKUP1	-	TIM2_CH1_ETR	-	-	-	-	-	USART2_CTS	-	-	-	-	-	TIMx_IC1	EVENTOUT
PA1	-	TIM2_CH2	-	-	-	-	-	USART2_RTS	-	-	[SEG0]	-	-	TIMx_IC2	EVENTOUT
PA2	-	TIM2_CH3	-	TIM9_CH1	-	-	-	USART2_TX	-	-	[SEG1]	-	-	TIMx_IC3	EVENTOUT
PA3	-	TIM2_CH4	-	TIM9_CH2	-	-	-	USART2_RX	-	-	[SEG2]	-	-	TIMx_IC4	EVENTOUT
PA4	-	-	-	-	-	SPI1_NSS	-	USART2_CK	-	-	-	-	-	TIMx_IC1	EVENTOUT
PA5	-	TIM2_CH1_ETR	-	-	-	SPI1_SCK	-	-	-	-	-	-	-	TIMx_IC2	EVENTOUT
PA6	-	-	TIM3_CH1	TIM10_CH1	-	SPI1_MISO	-	-	-	-	[SEG3]	-	-	TIMx_IC3	EVENTOUT
PA7	-	-	TIM3_CH2	TIM11_CH1	-	SPI1_MOSI	-	-	-	-	[SEG4]	-	-	TIMx_IC4	EVENTOUT
PA8	MCO	-	-	-	-	-	-	USART1_CK	-	-	[COM0]	-	-	TIMx_IC1	EVENTOUT
PA9	-	-	-	-	-	-	-	USART1_TX	-	-	[COM1]	-	-	TIMx_IC2	EVENTOUT
PA10	-	-	-	-	-	-	-	USART1_RX	-	-	[COM2]	-	-	TIMx_IC3	EVENTOUT
PA11	-	-	-	-	-	SPI1_MISO	-	USART1_CTS	-	-	-	-	-	TIMx_IC4	EVENTOUT
PA12	-	-	-	-	-	SPI1_MOSI	-	USART1_RTS	-	-	-	-	-	TIMx_IC1	EVENTOUT
PA13	JTMS-SWDIO	-	-	-	-	-	-	-	-	-	-	-	-	TIMx_IC2	EVENTOUT
PA14	JTCK-SWCLK	-	-	-	-	-	-	-	-	-	-	-	-	TIMx_IC3	EVENTOUT
PA15	JTDI	TIM2_CH1_ETR	-	-	-	SPI1_NSS	-	-	-	-	SEG17	-	-	TIMx_IC4	EVENTOUT
PB0	-	-	TIM3_CH3	-	-	-	-	-	-	-	[SEG5]	-	-	-	EVENTOUT
PB1	-	-	TIM3_CH4	-	-	-	-	-	-	-	[SEG6]	-	-	-	EVENTOUT
PB2	BOOT1	-	-	-	-	-	-	-	-	-	-	-	-	-	EVENTOUT
PB3	JTDO	TIM2_CH2	-	-	-	SPI1_SCK	-	-	-	-	[SEG7]	-	-	-	EVENTOUT
PB4	NJTRST	-	TIM3_CH1	-	-	SPI1_MISO	-	-	-	-	[SEG8]	-	-	-	EVENTOUT

Table 9. Alternate function input/output (continued)

Port name	Digital alternate function number														
	AFIO0	AFIO1	AFIO2	AFIO3	AFIO4	AFIO5	AFOI6	AFIO7	AFIO8	AFIO9	AFIO11	AFIO12	AFIO13	AFIO14	AFIO15
	Alternate function														
	SYSTEM	TIM2	TIM3/4	TIM9/10/11	I2C1/2	SPI1/2	N/A	USART1/2/3	N/A	N/A	LCD	N/A	N/A	RI	SYSTEM
PC11	-	-	-	-	-	-	-	USART3_RX	-	-	COM5 / SEG29 / SEG41	-	-	TIMx_IC4	EVENTOUT
PC12	-	-	-	-	-	-	-	USART3_CK	-	-	COM6 / SEG30 / SEG42	-	-	TIMx_IC1	EVENTOUT
PC13-WKUP2	-	-	-	-	-	-	-	-	-	-	-	-	-	TIMx_IC2	EVENTOUT
PC14-OSC32_IN	-	-	-	-	-	-	-	-	-	-	-	-	-	TIMx_IC3	EVENTOUT
PC15-OSC32_OUT	-	-	-	-	-	-	-	-	-	-	-	-	-	TIMx_IC4	EVENTOUT
PD0	-	-	-	TIM9_CH1	-	SPI2_NSS	-	-	-	-	-	-	-	TIMx_IC1	EVENTOUT
PD1	-	-	-	-	-	SPI2_SCK	-	-	-	-	-	-	-	TIMx_IC2	EVENTOUT
PD2	-	-	TIM3_ETR	-	-	-	-	-	-	-	COM7 / SEG31 / SEG43	-	-	TIMx_IC3	EVENTOUT
PD3	-	-	-	-	-	SPI2_MISO	-	USART2_CTS	-	-	-	-	-	TIMx_IC4	EVENTOUT
PD4	-	-	-	-	-	SPI2_MOSI	-	USART2_RTS	-	-	-	-	-	TIMx_IC1	EVENTOUT
PD5	-	-	-	-	-	-	-	USART2_TX	-	-	-	-	-	TIMx_IC2	EVENTOUT
PD6	-	-	-	-	-	-	-	USART2_RX	-	-	-	-	-	TIMx_IC3	EVENTOUT
PD7	-	-	-	TIM9_CH2	-	-	-	USART2_CK	-	-	-	-	-	TIMx_IC4	EVENTOUT
PD8	-	-	-	-	-	-	-	USART3_TX	-	-	-	-	-	TIMx_IC1	EVENTOUT
PD9	-	-	-	-	-	-	-	USART3_RX	-	-	-	-	-	TIMx_IC2	EVENTOUT
PD10	-	-	-	-	-	-	-	USART3_CK	-	-	-	-	-	TIMx_IC3	EVENTOUT
PD11	-	-	-	-	-	-	-	USART3_CTS	-	-	-	-	-	TIMx_IC4	EVENTOUT
PD12	-	-	TIM4_CH1	-	-	-	-	USART3_RTS	-	-	-	-	-	TIMx_IC1	EVENTOUT

Table 14. Embedded reset and power control block characteristics (continued)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V_{PVD0}	Programmable voltage detector threshold 0	Falling edge	1.8	1.85	1.88	V
		Rising edge	1.88	1.94	1.99	
V_{PVD1}	PVD threshold 1	Falling edge	1.98	2.04	2.09	
		Rising edge	2.08	2.14	2.18	
V_{PVD2}	PVD threshold 2	Falling edge	2.20	2.24	2.28	
		Rising edge	2.28	2.34	2.38	
V_{PVD3}	PVD threshold 3	Falling edge	2.39	2.44	2.48	
		Rising edge	2.47	2.54	2.58	
V_{PVD4}	PVD threshold 4	Falling edge	2.57	2.64	2.69	
		Rising edge	2.68	2.74	2.79	
V_{PVD5}	PVD threshold 5	Falling edge	2.77	2.83	2.88	
		Rising edge	2.87	2.94	2.99	
V_{PVD6}	PVD threshold 6	Falling edge	2.97	3.05	3.09	
		Rising edge	3.08	3.15	3.20	
V_{hyst}	Hysteresis voltage	BOR0 threshold	-	40	-	mV
		All BOR and PVD thresholds excepting BOR0	-	100	-	

1. Guaranteed by characterization results.
2. Valid for device version without BOR at power up. Please see option "T" in Ordering information scheme for more details.

6.3.4 Supply current characteristics

The current consumption is a function of several parameters and factors such as the operating voltage, ambient temperature, I/O pin loading, device software configuration, operating frequencies, I/O pin switching rate, program location in memory and executed binary code. The current consumption is measured as described in *Figure 14: Current consumption measurement scheme*.
All Run-mode current consumption measurements given in this section are performed with a reduced code that gives a consumption equivalent to Dhrystone 2.1 code.

The current consumption values are derived from the tests performed under ambient temperature T_A=25°C and V_{DD} supply voltage conditions summarized in *Table 13: General operating conditions*, unless otherwise specified. The MCU is placed under the following conditions:

The MCU is placed under the following conditions:

- V_{DD} = 3.6 V
- All I/O pins are configured in analog input mode.
- All peripherals are disabled except when explicitly mentioned
- The Flash memory access time, 64-bit access and prefetch is adjusted depending on f_{HCLK} frequency and voltage range to provide the best CPU performance.
- When the peripherals are enabled $f_{APB1} = f_{APB2} = f_{AHB}$
- When PLL is ON, the PLL inputs are equal to HSI = 16 MHz (if internal clock is used) or HSE = 16 MHz (if HSE bypass mode is used).
- The HSE user clock applied to OSC_IN input follows the characteristics specified in *Table 26: High-speed external user clock characteristics*.

Static latch-up

Two complementary static tests are required on six parts to assess the latch-up performance:

- A supply overvoltage is applied to each power supply pin
- A current injection is applied to each input, output and configurable I/O pin

These tests are compliant with EIA/JESD 78A IC latch-up standard.

Table 40. Electrical sensitivities

Symbol	Parameter	Conditions	Class
LU	Static latch-up class	T_A = +105 °C conforming to JESD78A	II level A

6.3.12 I/O current injection characteristics

As a general rule, current injection to the I/O pins, due to external voltage below V_{SS} or above V_{DD} (for standard pins) should be avoided during normal product operation. However, in order to give an indication of the robustness of the microcontroller in cases when abnormal injection accidentally happens, susceptibility tests are performed on a sample basis during device characterization.

Functional susceptibility to I/O current injection

While a simple application is executed on the device, the device is stressed by injecting current into the I/O pins programmed in floating input mode. While current is injected into the I/O pin, one at a time, the device is checked for functional failures.

The failure is indicated by an out of range parameter: ADC error, out of spec current injection on adjacent pins or other functional failure (for example reset, oscillator frequency deviation, LCD levels, etc.).

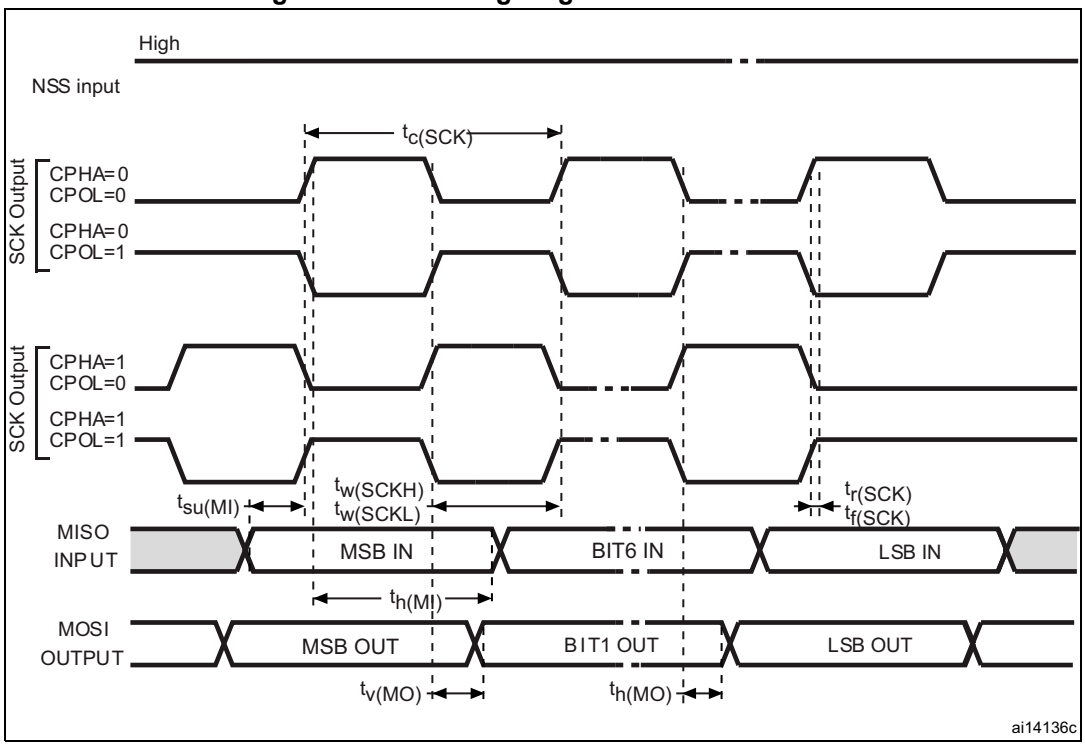
The test results are given in *Table 41*.

Table 41. I/O current injection susceptibility

Symbol	Description	Functional susceptibility		Unit
		Negative injection	Positive injection	
I_{INJ}	Injected current on all 5 V tolerant (FT) pins	-5	+0	mA
	Injected current on any other pin	-5	+5	

Note: It is recommended to add a Schottky diode (pin to ground) to analog pins which may potentially inject negative currents.

Figure 24. SPI timing diagram - master mode(1)



1. Measurement points are done at CMOS levels: $0.3V_{DD}$ and $0.7V_{DD}$.

USB characteristics

The USB interface is USB-IF certified (full speed).

Table 50. USB startup time

Symbol	Parameter	Max	Unit
$t_{STARTUP}$(1)	USB transceiver startup time	1	µs

1. Guaranteed by design.

Figure 28. Maximum dynamic current consumption on V_{REF+} supply pin during ADC conversion

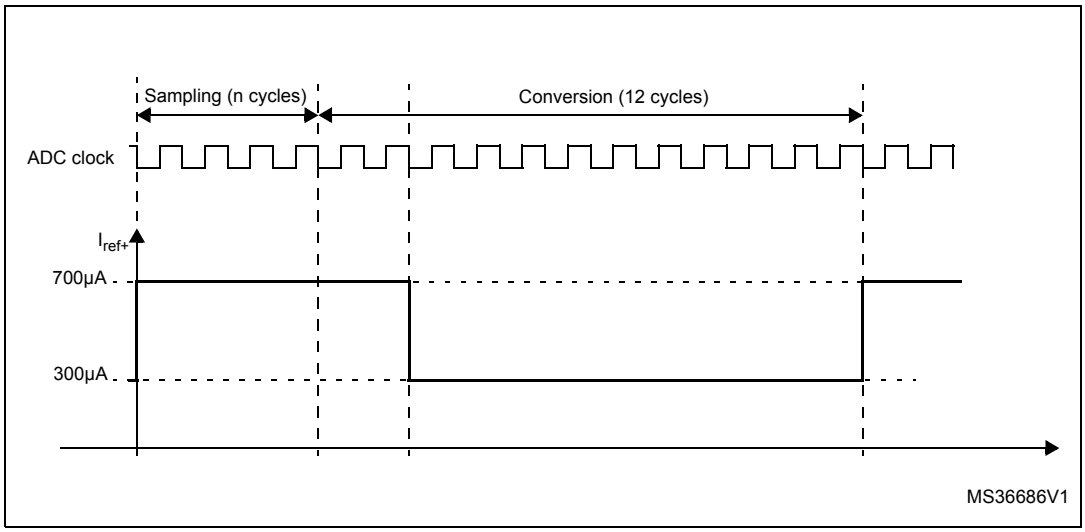


Table 56. Maximum source impedance R_{AIN} max(1)

Ts (µs)	R_{AIN} max (kOhm)				Ts (cycles) f_{ADC}= 16 MHz(2)
	Multiplexed channels		Direct channels		
	2.4 V < V_{DDA}< 3.6 V	1.8 V < V_{DDA} < 2.4 V	2.4 V < V_{DDA}< 3.3 V	1.8 V < V_{DDA} < 2.4 V	
0.25	Not allowed	Not allowed	0.7	Not allowed	4
0.5625	0.8	Not allowed	2.0	1.0	9
1	2.0	0.8	4.0	3.0	16
1.5	3.0	1.8	6.0	4.5	24
3	6.8	4.0	15.0	10.0	48
6	15.0	10.0	30.0	20.0	96
12	32.0	25.0	50.0	40.0	192
24	50.0	50.0	50.0	50.0	384

1. Guaranteed by design.
2. Number of samples calculated for **f_{ADC} = 16 MHz. F**or **f_{ADC} = 8 and 4 MHz the number of sampling cycles can be reduced with respect to the minimum sampling time Ts (us).**

General PCB design guidelines

Power supply decoupling should be performed as shown in The 10 nF capacitors should be ceramic (good quality). They should be placed as close as possible to the chip.

6.3.21 LCD controller (STM32L152xx only)

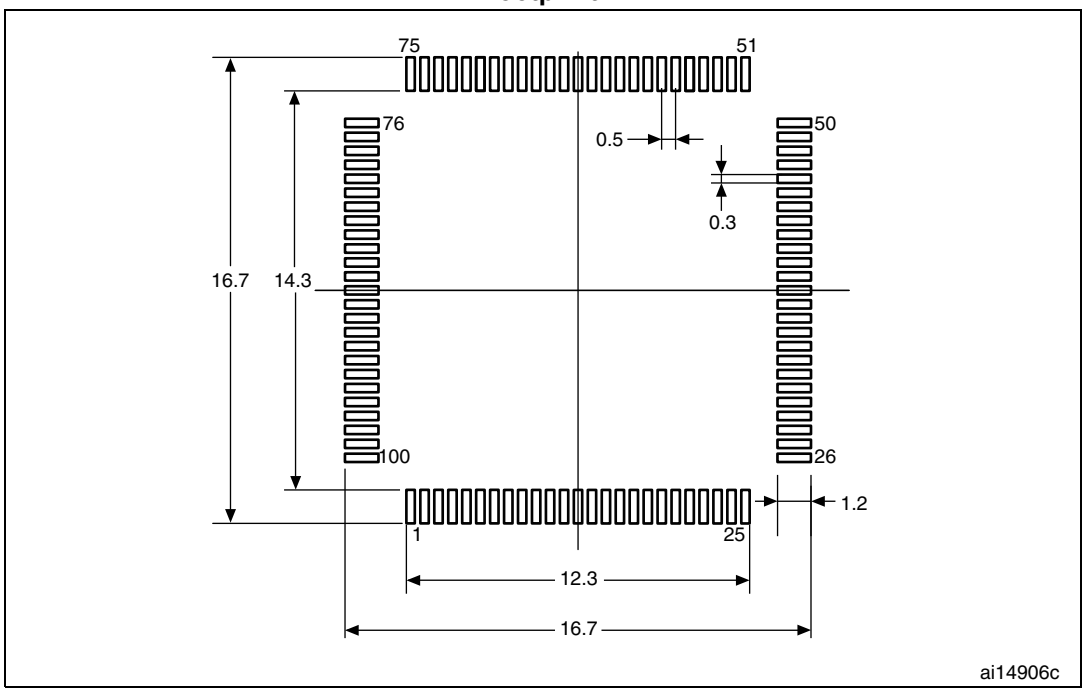
The STM32L152xx embeds a built-in step-up converter to provide a constant LCD reference voltage independently from the V_{DD} voltage. An external capacitor C_{ext} must be connected to the V_{LCD} pin to decouple this converter.

Table 62. LCD controller characteristics

Symbol	Parameter	Min	Typ	Max	Unit
V_{LCD}	LCD external voltage	-	-	3.6	V
V_{LCD0}	LCD internal reference voltage 0	-	2.6	-	
V_{LCD1}	LCD internal reference voltage 1	-	2.73	-	
V_{LCD2}	LCD internal reference voltage 2	-	2.86	-	
V_{LCD3}	LCD internal reference voltage 3	-	2.98	-	
V_{LCD4}	LCD internal reference voltage 4	-	3.12	-	
V_{LCD5}	LCD internal reference voltage 5	-	3.26	-	
V_{LCD6}	LCD internal reference voltage 6	-	3.4	-	
V_{LCD7}	LCD internal reference voltage 7	-	3.55	-	
C_{ext}	V_{LCD} external capacitance	0.1	-	2	µF
I_{LCD}(1)	Supply current at V_{DD} = 2.2 V	-	3.3	-	µA
	Supply current at V_{DD} = 3.0 V	-	3.1	-	
R_{Htot}(2)	Low drive resistive network overall value	5.28	6.6	7.92	MΩ
R_L(2)	High drive resistive network total value	192	240	288	kΩ
V_{44}	Segment/Common highest level voltage	-	-	V_{LCD}	V
V_{34}	Segment/Common 3/4 level voltage	-	3/4 V_{LCD}	-	V
V_{23}	Segment/Common 2/3 level voltage	-	2/3 V_{LCD}	-	
V_{12}	Segment/Common 1/2 level voltage	-	1/2 V_{LCD}	-	
V_{13}	Segment/Common 1/3 level voltage	-	1/3 V_{LCD}	-	
V_{14}	Segment/Common 1/4 level voltage	-	1/4 V_{LCD}	-	
V_0	Segment/Common lowest level voltage	0	-	-	
ΔVxx(3)	Segment/Common level voltage error T_A = -40 to 85 °C	-	-	±50	mV

1. LCD enabled with 3 V internal step-up active, 1/8 duty, 1/4 bias, division ratio= 64, all pixels active, no LCD connected
2. Guaranteed by design.
3. Guaranteed by characterization results.

Figure 33. LQPF100 14 x 14 mm, 100-pin low-profile quad flat package recommended footprint

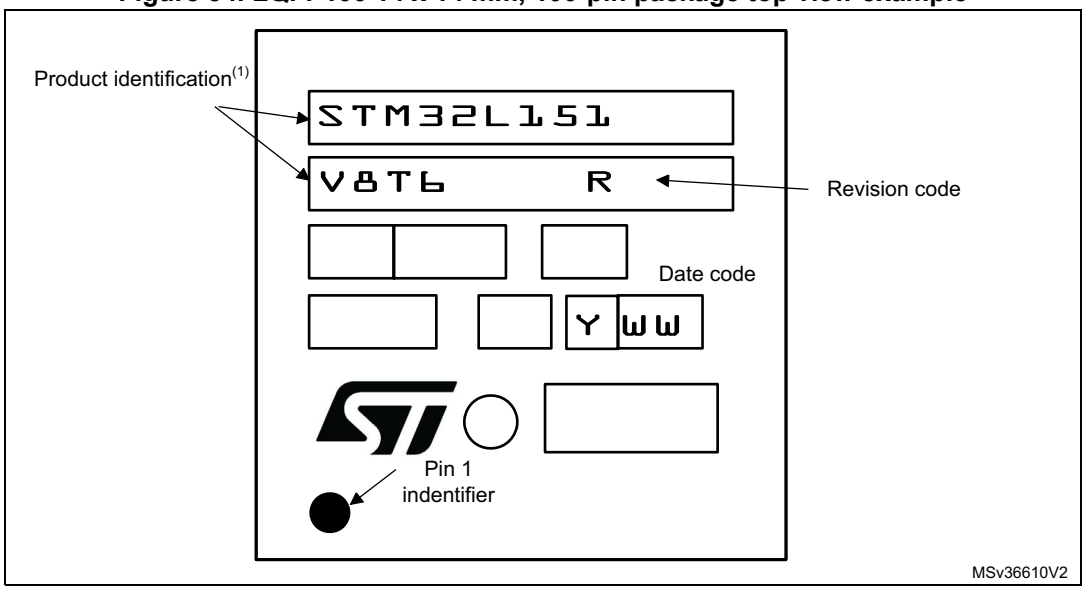


1. Dimensions are in millimeters.

LQFP100 device marking

The following figure gives an example of topside marking orientation versus pin 1 identifier location.

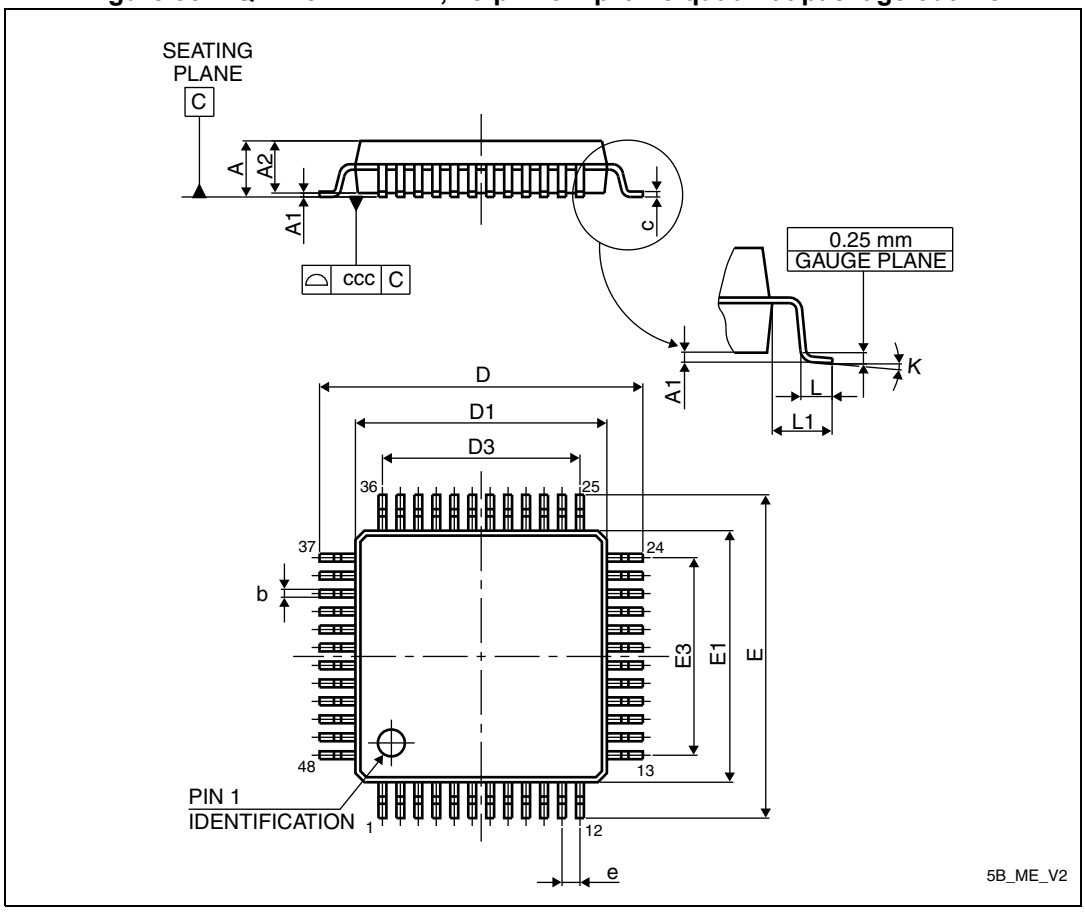
Figure 34. LQFP100 14 x 14 mm, 100-pin package top view example



1. Parts marked as “ES”, “E” or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering samples to run qualification activity.

7.3 LQFP48 7 x 7 mm, 48-pin low-profile quad flat package information

Figure 38. LQFP48 7 x 7 mm, 48-pin low-profile quad flat package outline



1. Drawing is not to scale.

Table 73. Document revision history (continued)

Date	Revision	Changes
25-Feb-2011	4 (continued)	Updated *Table 23: Typical and maximum current consumptions in Standby mode on page 66* (I_{DD} (WU from Standby) instead of (I_{DD} (WU from Stop). *Table 25: Low-power mode wakeup timings on page 69*: updated condition for Wakeup from Stop mode, regulator in Run mode; updated max values for Wakeup from Stop mode, regulator in low power mode; updated max values for $t_{WUSTDBY}$. *Table 24: Peripheral current consumption on page 67*: updated values for column Low power sleep and run; updated Flash values; renamed ADC1 to ADC; updated $I_{DD\ (LCD)}$ value; updated units; added values for $I_{DD\ (RTC)}$ and $I_{DD\ (IWDG)}$; updated footnote 1 and 3; added foot note 2 concerning ADC. *Table 26: High-speed external user clock characteristics on page 70*: added min value for $t_{w(HSE)}/t_{w(HSE)}$ OSC_IN high or low time; added max value for $t_{r(HSE)}/t_{f(HSE)}$ OSC_IN rise or fall time; updated I_L for typ and max values. *Table 27: Low-speed external user clock characteristics on page 71*: updated max value for I_L. *Table 28: HSE oscillator characteristics on page 72*: renamed i_2 as I_{HSE} and updated max value; updated max values for $I_{DD(HSE)}$. *Table 29: LSE oscillator characteristics (fLSE = 32.768 kHz) on page 73*: updated max value for I_{LSE}. *Table 30: HSI oscillator characteristics on page 75*: updated some min and max values for ACC_{HSI}. *Table 32: MSI oscillator characteristics on page 76*: updated parameter, typ, and max values for $D_{VOLT(MSI)}$. *Table 35: Flash memory and data EEPROM characteristics on page 78*: updated typ values for t_{prog}. *Table 44: I/O AC characteristics on page 84*: updated some max values for 01, 10, and 11; updated min value; updated footnotes. *Table 55: ADC accuracy on page 95*: updated typ values and some of the test conditions for ENOB, SINAD, SNR, and THD. *Table 57: DAC characteristics on page 99*: updated footnote 7 and added footnote 8. Updated leakage value in *Figure 27: Typical connection diagram using the ADC*. Added *Figure 28: Maximum dynamic current consumption on VREF+ supply pin during ADC conversion*. Added *Table 56: R_{AIN} max for f_{ADC} = 16 MHz on page 98* *Figure 29: Power supply and reference decoupling (VREF+ not connected to VDDA)*: replaced all 10 nF capacitors with 100 nF capacitors. *Figure 30: Power supply and reference decoupling (VREF+ connected to VDDA)*: replaced 10 nF capacitor with 100 nF capacitor.

Table 73. Document revision history (continued)

Date	Revision	Changes
12-Nov-2013	9 (continued)	Updated *Table 54: ADC characteristics* and *Figure 27: Typical connection diagram using the ADC*. *Table 58: Temperature sensor calibration values* was previously in *Section 3.10.1: Temperature sensor*. Updated *Table 59: Temperature sensor characteristics*. In *Table 61: Comparator 2 characteristics*, parameter dThreshold/dt, replaced any occurrence of “VREF+” by “V_{REFINT}”Updated *Table 63: LQPF100 14 x 14 mm, 100-pin low-profile quad flat package mechanical data*, *Table 64: LQFP64 10 x 10 mm 64-pin low-profile quad flat package mechanical data*, *Table 65: LQFP48 7 x 7 mm, 48-pin low-profile quad flat package mechanical data* and *Table 66: UFQFPN48 7 x 7 mm, 0.5 mm pitch, ultra thin fine-pitch quad flat no-lead package mechanical data*. Updated *Figure 33: LQFP100 recommended footprint*. Updated *Figure 46: TFBGA64 - 5.0x5.0x1.2 mm, 0.5 mm pitch, thin fine-pitch ball grid array package outline* title. Remove minimum and typical values of A dimension in *Table 67: UFBGA100 7 x 7 x 0.6 mm 0.5 mm pitch, ultra thin fine-pitch ball grid array package mechanical data* Deleted second footnote in *Figure 42: UFQFPN48 recommended footprint*. Updated *Section 8: Ordering information* title and added first sentence. Changed BOR disabled option identifier in *Table 72: Ordering information scheme*.
22-Jul-2014	10	Updated *Figure 14*, *Figure 15*. Updated *Table 5*. Updated *Figure 6.3.4*. Updated note *5* inside *Table 54*. Updated Ro value inside *Table 54*.

Table 73. Document revision history (continued)

Date	Revision	Changes
30-Jan-2015	11	Updated DMIPS features in cover page and *Section 2: Description*. Updated *Table 8: STM32L151x6/8/B and STM32L152x6/8/B pin definitions* and *Table 9: Alternate function input/output* putting additional functions. Updated package top view marking in *Section 7.1: Package mechanical data*. Updated *Figure 9: Memory map*. Updated *Table 56: Maximum source impedance RAIN max* adding note 2. Updated *Table 72: Ordering information scheme*.
28-Apr-2016	12	Updated *Section 7: Package information* structure: Paragraph titles and paragraph heading level. Updated *Section 7: Package information* for all package device markings, adding text for device orientation versus pin 1/ ball A1 identifier. Updated *Figure 34: LQFP100 14 x 14 mm, 100-pin package top view example* removing gate mark. Updated *Table 64: LQFP64 10 x 10 mm, 64-pin low-profile quad flat package mechanical data*. Updated *Section 7.5: UFBGA100 7 x 7 mm, 0.5 mm pitch, ultra thin fine-pitch ball grid array package information* adding *Table 68: UFBGA100 7 x 7 mm, 0.5 mm pitch, recommended PCB design rules* and *Figure 45: UFBGA100 7 x 7 mm, 0.5 mm pitch, package recommended footprint*. Updated *Section 7.6: TFBGA64 5 x 5 mm, 0.5 mm pitch, thin fine-pitch ball grid array package information* adding *Table 70: TFBGA64 5 x 5 mm, 0.5 mm pitch, recommended PCB design rules* and changing *Figure 48: TFBGA64, 5 x 5 mm, 0.5 mm pitch, recommended footprint*. Updated *Table 16: Embedded internal reference voltage* temperature coefficient at 100ppm/°C. Updated note 3 below *Table 16*. Updated *Table 61: Comparator 2 characteristics* new maximum threshold voltage temperature coefficient at 100ppm/°C. Updated *Table 39: ESD absolute maximum ratings* CDM class. Updated all the notes, removing ‘not tested in production’. Updated *Table 10: Voltage characteristics* adding note about V_{REF-} pin. Updated *Table 5: Working mode-dependent functionalities (from Run/active down to standby)* LSI and LSE functionalities putting “Y” in Standby mode. Removed note 1 below *Figure 2: Clock tree*. Updated *Table 57: DAC characteristics* resistive load.